

Demonstration board for EVALSTGAP2SICD isolated 4 A half-bridge gate driver



Features

- **Board**
 - High voltage rail up to 1200 V
 - Negative gate driving
 - On-board isolated DC-DC converters to supply high-side and low-side gate drivers, fed by VAUX = 5 V, with 5.2 kV maximum isolation
 - VDD logic supplied by on-board generated 3.3 V or VAUX = 5V
 - Easy jumper selection of driving voltage configuration: +17/0 V; +17/-3 V; +19/0 V; +19/-3 V;
- **Device**
 - Driver current capability: 4 A source/sink @ 25°C
 - 4 A Miller CLAMP
 - Short propagation delay: 75 ns
 - UVLO function
 - Configurable interlocking function
 - Dedicated SD and BRAKE pins
 - Gate driving voltage up to 26 V
 - 3.3 V, 5 V TTL/CMOS inputs with hysteresis
 - Temperature shutdown protection
 - Standby function

| Product status link |
|--------------------------------|
| EVALSTGAP2SICD |

Description

The EVALSTGAP2SICD is an half bridge evaluation board designed to evaluate the STGAP2SiCD isolated dual gate driver.

The gate driver is characterized by 4 A current capability and rail-to-rail outputs, making the device suitable also for high power applications such as motor drivers in industrial applications equipped with SiC power switches.

The device integrates protection functions: dedicated SD and BRAKE pins are available, UVLO and thermal shutdown are included to easily design high reliability systems, and the interlocking function prevents outputs from being high at the same time.

The device allows implementing negative gate driving, and the on-board isolated DC-DC converters allows working with optimized driving voltage for SiC MOSFETs.

The EVALSTGAP2SICD board allows evaluating all the STGAP2SiCD features while driving a half-bridge power stage with voltage rating up to 1200 V in TO-220 or TO-247 package.

The board allows easily selecting and modifying the values of relevant external components in order to ease driver performance evaluation under different applicative conditions and fine pre-tuning of final application components.

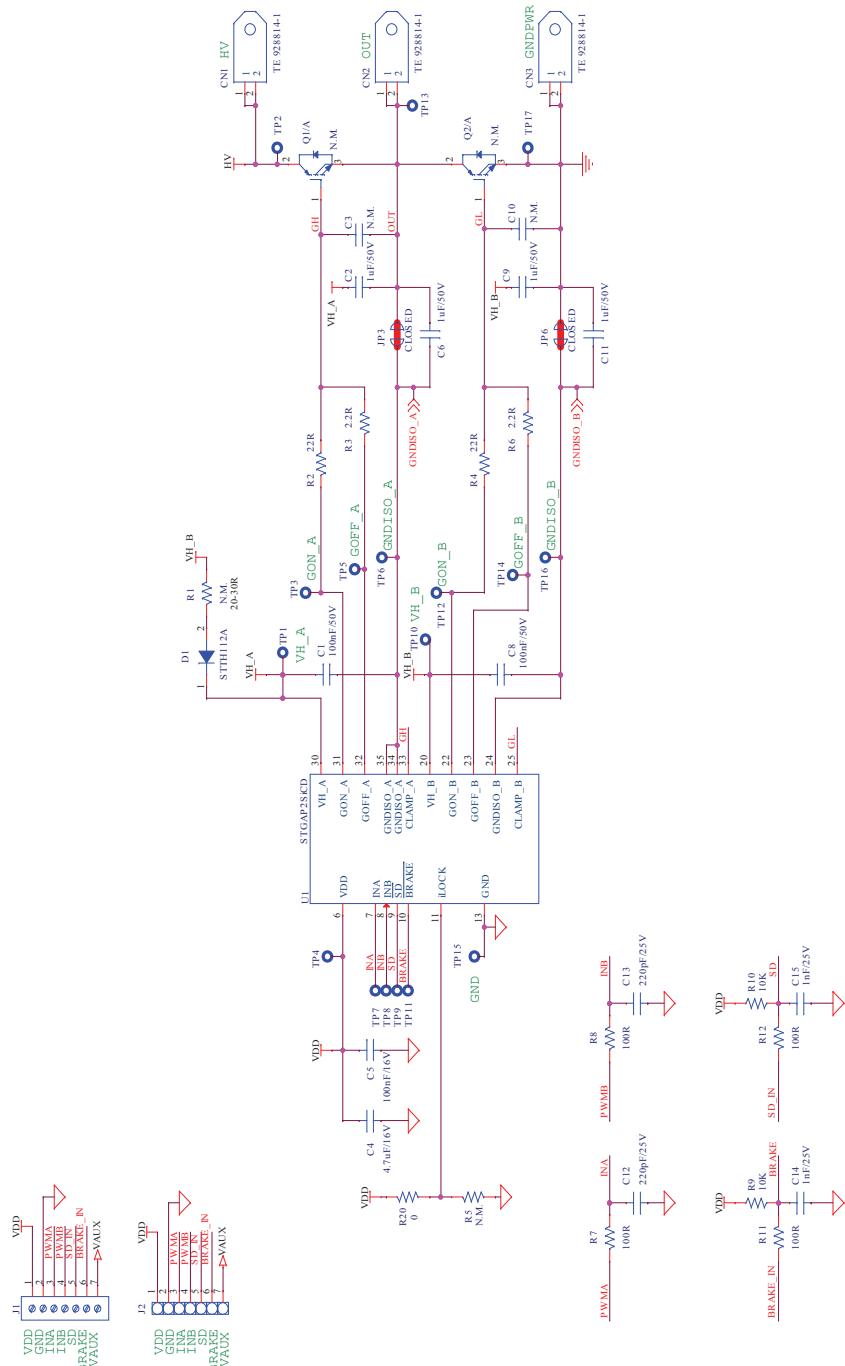
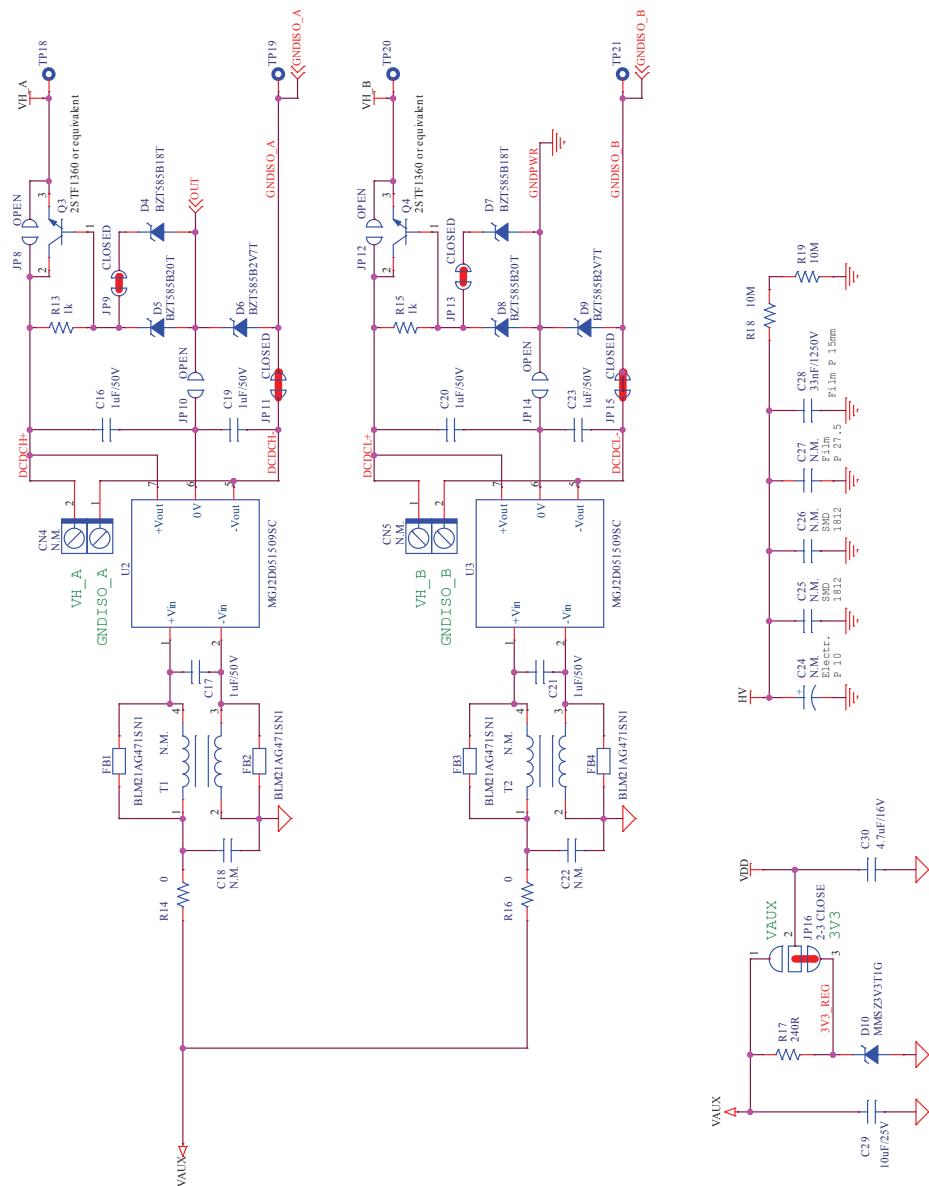
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Schematic diagram
Figure 1. EVALSTGAP2SICD schematic – gate driver


Figure 2. EVALSTGAP2SICD circuit schematic – supply, connectors and decoupling


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Bill of material

Table 1. EVALSTGAP2SICD - Bill of Material

| Part Reference | Part value | Part description |
|---------------------------------|---------------------------|--|
| CN1, CN2, CN3 | TE 928814-1 | Tab FASTON 250 Horizontal, 5.08 mm |
| CN4, CN5 | N.M. | Connector terminal block T.H. 2 POS 5.08 mm |
| C1, C8 | 100 nF / 50 V | Ceramic capacitor, SMT 1206 |
| C2, C6, C9, C11 | 1 µF / 50 V | Ceramic capacitor, SMT 0805 |
| C3, C10, C18, C22 | N.M. | Ceramic capacitor, SMT 0603 |
| C4, C30 | 4.7 µF / 16 V | Ceramic capacitor, SMT 0603 |
| C5 | 100 nF / 16 V | Ceramic capacitor, SMT 0603 |
| C12, C13 | 220 pF / 25 V | Ceramic capacitor, SMT 0603 |
| C14, C15 | 1 nF / 25 V | Ceramic capacitor, SMT 0603 |
| C16, C17, C19, C20, C21, C23 | 1 µF / 50 V | Ceramic capacitor, SMT 0603 |
| C24 | N.M. | THT electrolytic capacitor, P 10 mm |
| C25, C26 | N.M. | Ceramic capacitor, SMT 1812 |
| C27 | N.M. | Film capacitor, P 27.5 mm |
| C28 | 33 nF / 1250 V | Film capacitor, P 15 mm |
| C29 | 10 µF / 25 V | Ceramic capacitor, SMT 0805 |
| D1 | STTH112A | High voltage ultrafast rectifier, SMA |
| D4, D7 | BTZT585B18T | Surface mount precision Zener diode, SOD523 |
| D5, D8 | BZT585B20T | Surface mount precision Zener diode, SOD523 |
| D6, D9 | BZT585B2V7T | Surface mount precision Zener diode, SOD523 |
| D10 | MMSZ3V3T1G | Zener voltage regulator 500 mW, SOD-123 |
| FB1, FB2, FB3, FB4 | BLM21AG471SN1 | Ferrite beads, SMT 0805 |
| JP3, JP6, JP9, JP11, JP13, JP15 | Closed | SMT jumper |
| JP8, JP10, JP12, JP14 | Open | SMT jumper |
| JP16 | Closed 2-3 | SMT jumper |
| J1 | WE691243110007 or similar | Connector terminal block T.H. 7 POS 3.5 mm |
| J2 | Pin strip | Strip connector 7 pos, 2.54 mm |
| Q1, Q2 | N.M. | N-channel IGBT or MOSFET up to 1700 V, TO-247 |
| Q1A, Q2A | N.M. | N-channel IGBT or MOSFET up to 1700 V, TO-220 |
| Q3, Q4 | 2STF1360 | Low voltage fast-switching NPN power transistors, SOT-89 |
| R1 | N.M. | Chip resistor, SMT 1206 |
| R2, R4 | 22 Ω | Chip resistor, SMT 1210 |
| R3, R6 | 2.2 Ω | Chip resistor, SMT 1210 |
| R5 | N.M. | Chip resistor, SMT 0603 |
| R7, R8, R11, R12 | 100 Ω | Chip resistor, SMT 0603 |
| R9, R10 | 10 kΩ | Chip resistor, SMT 0603 |
| R13, R15 | 1 kΩ | Chip resistor, SMT 0603 |
| R14, R16, R20 | 0 Ω | Chip resistor, SMT 0603 |
| R17 | 240 Ω | Chip resistor, SMT 0805 |
| R18,R19 | 10 MΩ | Chip resistor, SMT 1206 |

| Part Reference | Part value | Part description |
|--|---------------|---|
| TP1, TP2, TP3, TP4, TP5, TP6, TP7, TP8, TP9, TP10, TP11, TP12, TP13, TP14, TP15, TP16, TP17 | N.M. | Loop test point, THT |
| TP18, TP19, TP20, TP21 | N.M. | Pad test point, SMD 1.5 mm |
| T1, T2 | N.M. | Common mode choke, SMD 4.7x4.5 mm |
| U1 | STGAP2SICD | Galvanically isolated 4 A dual gate driver for SiC MOSFETs, SO-36W |
| U2, U3 | MGJ2D051509SC | Murata 5.2 kVDC Isolated 2W Gate Drive DC/DC converters |

3 Layout and component placements

Figure 3. EVALSTGAP2SICD – Layout (component placement top view)

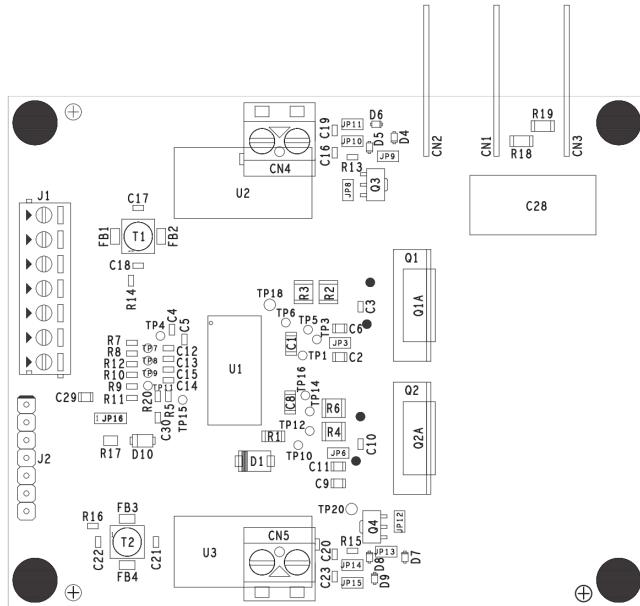


Figure 4. EVALSTGAP2SICD – Layout (component placement bottom view)

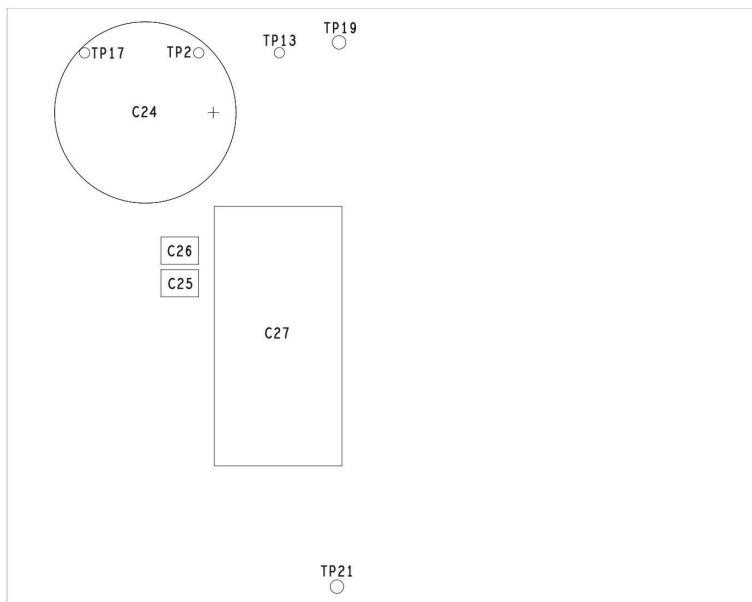


Figure 5. EVALSTGAP2SICD – Layout (top layer)

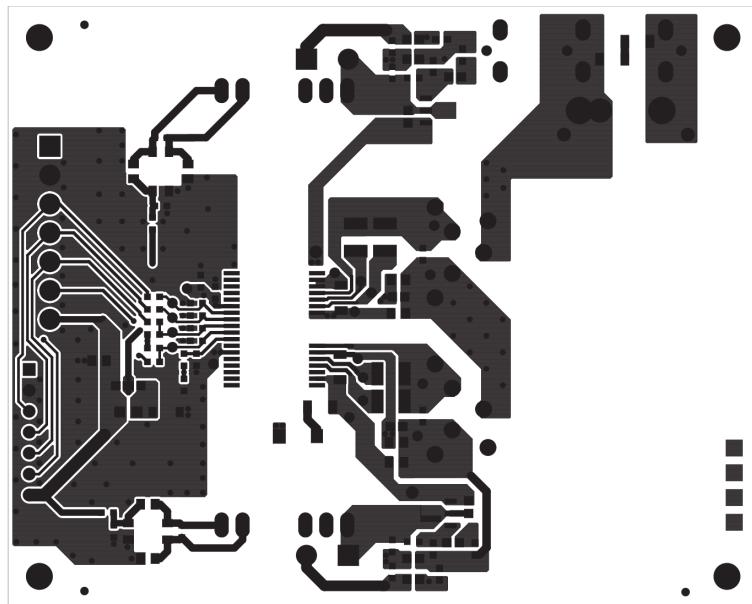
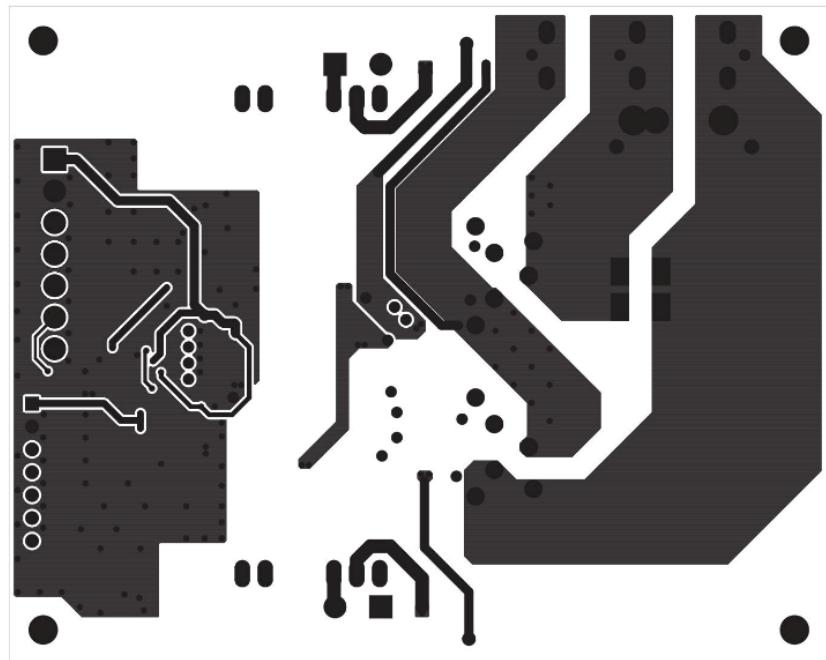


Figure 6. EVALSTGAP2SICD – Layout (bottom layer)



Revision history

Table 2. Document revision history

| Date | Version | Changes |
|-------------|---------|------------------|
| 29-Oct-2021 | 1 | Initial release. |

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